## Applicant(s)/Patent Under Application/Control No. Reexamination 10/049,869 KERSTEN ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 1714 Tae H Yoon **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY 04-1994 Shibata et al. 525/314 US-5,306,779 Α 525/191 US-6,300,418 10-2001 Brzoskowski et al. US-C US-D US-Ε US-F US-G US-Н USı US-J US-Κ US-US-Μ FOREIGN PATENT DOCUMENTS Document Number Date Name Classification Country Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

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